NEW AND/OR INTERESTING IN MICROSCOPY

- Paul Smith, formerly of Oxford Instruments and Link Analytical, as joined RÖNTEC, the German manufacturer of premium EDX systems as President and CEO of RÖNTEC USA, Inc. The company is a global supplier specializing in low LN2 consumption UHV cryo-cooled EDX detectors and will display their systems at M&M '99, booths 1016-1018.
- Optical Microscopy in the Next Millenium, a special 2 day pre-meeting congress prior to Microscopy & Microanalysis 99 is being organized by Brian Herman of the University of Texas Health Science Center at San Antonio. It will be held to provide a forum for the discussion of new technologies and applications of optical microscopy that will impact our understanding of biological structure and function in the next millenium. Approximately 36 internationally known speakers will cover a broad range of topics including multiphoton microscopy, confocal microscopy, fluorescence lifetime microscopy, near field/ atomic force microscopy, high resolution brightfield microscopy, laser tweezers, new fluorescent probes of cellular activity and protein-protein interaction, high throughput screening and drug development, automated image analysis, ion imaging, and more. Commercial vendors will be available for participants to visit during coffee breaks, continental breakfast and lunchtime. Information about the meeting can be obtained by visiting

the M&M 99 web site at: www.microscopy.com

● Scripps Institution of Oceanography's Analytical Facility anmnounces their AFM/STM services lab. Unlike SEM, AFM has the unique capability to provide high resolution imaging of biological samples in solution to maintain their structural integrity. We can also vary the solution (ph, buffers, etc.) to examine the bahavior of samples in vitro.

The total image size can be as high as 30 μ m x 30 μ m (lateral) and 7 μ m (height). High resolution images can produce feature sizes as low as ~5 nm (laterally) and subangstrom height resolution. Our capabilities for biological samples in solution and samples under environmental control (electrochemistry, humidity, and temperature) make us a unique facility compared to other contract AFM labs.

For more information, contact Kevin Walds, SIO Analytical Facility: (619)534-3558, eMail: kwalda@ucsd.edu

● Ventana Medical Systems, Inc. announces that it has successfully merged all of RMC business into its daily operations. Sales and marketing, as well as service will be moving to the headquarters at 3885 North Business Center Drive, Tucson, AZ.

Plans for a new 200,000 square foot facility were announced last quarter.

For more information, call (520)903-9366, toll free: (800) 227-2155, fax: (520)903-0132, www.ventanamed.com

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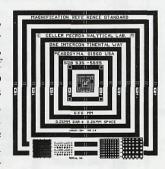
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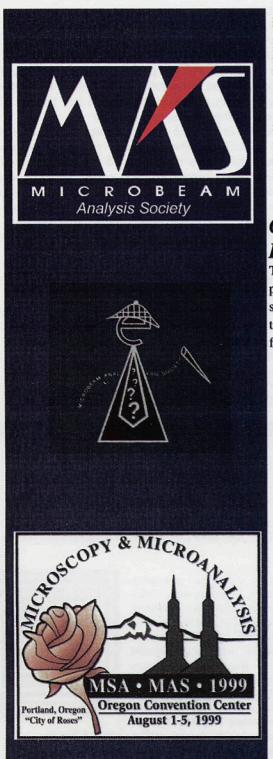
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nation and calibration procedures (ASTM E766-98). Visit us at booth 657 at the M&M '98 meeting. Also attend our exhibitor tutorial on magnification calibration on August 3 at 5:00 PM



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